



Condition Monitoring and Their Applications in Industry

Guest Editors:

Prof. Dr. Tat-Hean Gan

Brunel University London,
Uxbridge, United Kingdom

Prof. Dr. David Mba

Executive Office, University of the
Arts London, 272 High Holborn,
London WC1V 7EY, UK

Deadline for manuscript
submissions:

closed (30 April 2022)

Message from the Guest Editors

Dear Colleagues,

Critical assets such as machinery and structures are essential for economic activities across most sectors. Condition monitoring of these critical assets is essential for optimal usage. Such monitoring processes involve detecting faults at an early stage, diagnosing the fault source and monitoring and predicting the fault progression. Achieving these objectives successfully for both machinery and structures requires use of a range of data analysis techniques that are typically developed for the specific application. While numerous theoretical data analysis, machine learning and signal processing techniques have evolved, this Special Edition presents only industrial-application-based papers in which the latest condition monitoring techniques are applied to machinery and structures.

Keywords:

- Condition monitoring
- Machinery
- Structures
- Diagnosis
- Prognosis





an Open Access Journal by MDPI

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo

Dipartimento di Fisica,
Politecnico di Milano, Piazza L.
da Vinci 32, 20133 Milano, Italy

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Author Benefits

Open Access: free for readers, with article processing charges (APC) paid by authors or their institutions.

High Visibility: indexed within Scopus, SCIE (Web of Science), Inspec, CAPlus / SciFinder, and other databases.

Journal Rank: JCR - Q2 (*Engineering, Multidisciplinary*) / CiteScore - Q1 (*General Engineering*)

Contact Us

Applied Sciences Editorial Office
MDPI, St. Alban-Anlage 66
4052 Basel, Switzerland

Tel: +41 61 683 77 34
www.mdpi.com

mdpi.com/journal/applsci
applsci@mdpi.com
[X@Applsci](https://twitter.com/Applsci)